Search Notes

Applicatio	n/Control No.	Applicant(s)/Pat Reexamination	ent under
10/723,20	5	CHAMPLIN	
Examiner		Art Unit	
Frantz B.	Jean	2151	

SEARCHED					
Class	Subclass	Date	Examiner		
709	203, 201	6/24/2005	FJ		
	223-224				
	244				
707	10				
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INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
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SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
	DATE	EXMR
West, EPO, JPO, TDBD, OCR, Derwent; Invenor search; double patenting with US patent 6,598,090	6/24/2005	FJ
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